



AN 437

SIMS Analysis of Individual SiC Particles for Accurate Bulk Concentration Measurement

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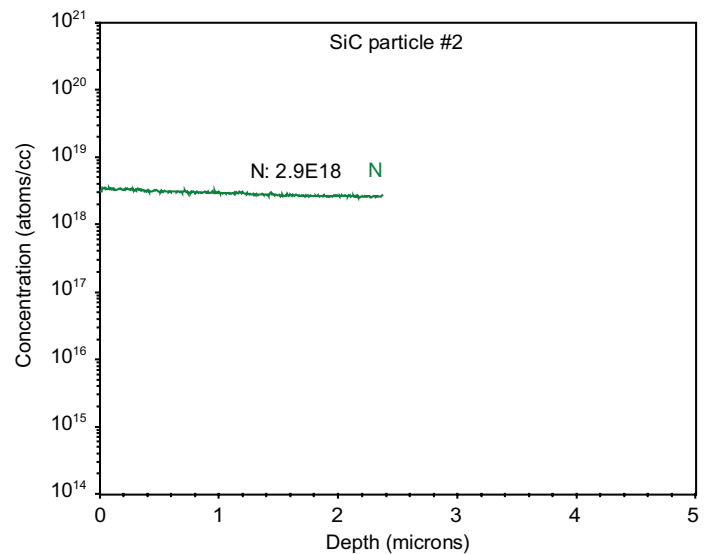
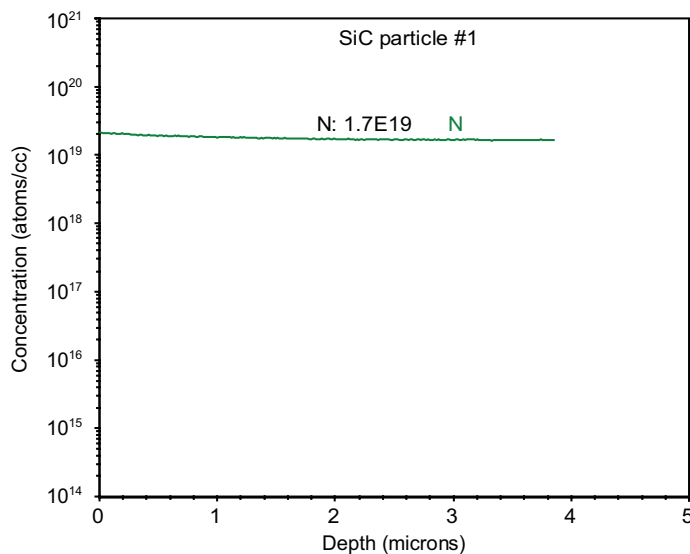
Discussion

Using a special sample preparation technique and a new SIMS analytical protocol, individual SiC particles with a size ranging from 100 μm to 500 μm in a SiC powder sample can be analyzed. This innovative approach eliminates contributions from surface contamination to bulk concentration.

Powder Size: 100-500 μm 

N profiles for two different SiC particles from the same batch of powder samples

The SIMS results for these two particles show good batch bulk concentration consistency.



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